

Title (en)

MULTI-STEP IMAGE ALIGNMENT METHOD FOR LARGE OFFSET DIE-DIE INSPECTION

Title (de)

BILDAUSRICHTUNGSVERFAHREN IN MEHREREN SCHRITTEN FÜR EINE GROSSE OFFSET-CHIP-CHIP-INSPEKTION

Title (fr)

PROCÉDÉ D'ALIGNEMENT D'IMAGE À ÉTAPES MULTIPLES POUR INSPECTION ENTRE PUCES À DÉCALAGE IMPORTANT

Publication

**EP 3698322 A1 20200826 (EN)**

Application

**EP 18867402 A 20181019**

Priority

- US 201762575304 P 20171020
- US 201816160515 A 20181015
- US 2018056600 W 20181019

Abstract (en)

[origin: US2019122913A1] A die-die inspection image can be aligned using a method or system configured to receive a reference image and a test image, determine a global offset and rotation angle from local sections on the reference image and test image, and perform a rough alignment de-skew of the test image prior to performing a fine alignment.

IPC 8 full level

**G06T 7/33** (2017.01); **G06T 7/00** (2017.01); **H01L 21/66** (2006.01)

CPC (source: EP KR US)

**G06T 3/14** (2024.01 - EP US); **G06T 3/20** (2013.01 - US); **G06T 3/608** (2013.01 - US); **G06T 7/001** (2013.01 - EP KR US); **G06T 7/337** (2016.12 - EP KR US); **G06T 7/74** (2016.12 - US); **H01L 21/67288** (2013.01 - US); **H01L 22/12** (2013.01 - KR); **H01L 22/20** (2013.01 - KR); **G06T 2207/20016** (2013.01 - EP US); **G06T 2207/20021** (2013.01 - US); **G06T 2207/20056** (2013.01 - EP US); **G06T 2207/20081** (2013.01 - EP US); **G06T 2207/30148** (2013.01 - EP KR US)

Designated contracting state (EPC)

AL AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO RS SE SI SK SM TR

Designated extension state (EPC)

BA ME

DOCDB simple family (publication)

**US 10522376 B2 20191231**; **US 2019122913 A1 20190425**; CN 111164646 A 20200515; EP 3698322 A1 20200826; EP 3698322 A4 20210602; JP 2021500740 A 20210107; JP 7170037 B2 20221111; KR 102412022 B1 20220622; KR 20200060519 A 20200529; TW 201928541 A 20190716; TW I774863 B 20220821; WO 2019079658 A1 20190425

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